

## LP SRAM SINGLE PORT HVT MODELS (NHVTPDSP, NHVTPGSP, PHVTPUSP)

### 1. CONDITIONS OF EXTRACTION

- Maturity: Pre production
- Geometrical extraction domain:
- Density  $1.15\mu\text{m}^2$ 
  - Pull Down Transistor :  $W=0.18\mu\text{m}$ ,  $L=0.1\mu\text{m}$
  - Pass Gate Transistor :  $W=0.12\mu\text{m}$ ,  $L=0.115\mu\text{m}$
  - Pull Up Transistor :  $W=0.11\mu\text{m}$ ,  $L=0.1\mu\text{m}$
- Temperature extraction domain:
  - $-40\text{ }^{\circ}\text{C}$  to  $150\text{ }^{\circ}\text{C}$
- Bias extraction domain:
  - Gate bias:  $0 \leq |V_{GS}| \leq 1.32\text{ V}$  ( $V_{dd} + 10\%$ )
  - Drain bias:  $0 \leq |V_{DS}| \leq 1.32\text{ V}$  ( $V_{dd} + 10\%$ )
  - Bulk bias:  $0 \leq |V_{BS}| \leq 1.32\text{ V}$  ( $V_{dd} + 10\%$ )

### 2. CONDITIONS OF SIMULATION

- Temperature:
 

25C
- Threshold Voltages:
 

$V_{TLIN} = V_{gs}$  for  $I_{ds} = 40\text{nA} \times (W_{drawn}/L_{drawn})$  at  $V_{ds} = 25\text{ mV}$  and  $V_{bs} = 0\text{ V}$ .

$V_{TSAT} = V_{gs}$  for  $I_{ds} = 40\text{nA} \times (W_{drawn}/L_{drawn})$  at  $V_{ds} = 1.2\text{ V}$  and  $V_{bs} = 0\text{ V}$
- Currents:
 

$I_{ON} = I_{ds}$  at  $V_{gs} = 1.2\text{ V}$ ,  $V_{ds} = 1.2\text{ V}$  and  $V_{bs} = 0\text{ V}$ .

$I_{OFF} = I_{ds}$  at  $V_{gs} = 0\text{ V}$ ,  $V_{ds} = 1.2\text{ V}$  and  $V_{bs} = 0\text{ V}$ .

$I_{G\_ON} = I_{gs}$  at  $V_{gs} = 1.2\text{ V}$ ,  $V_{ds} = 1.2\text{ V}$  and  $V_{bs} = 0\text{ V}$ .

$I_{G\_OFF} = I_{gs}$  at  $V_{gs} = 0\text{ V}$ ,  $V_{ds} = 1.2\text{ V}$  and  $V_{bs} = 0\text{ V}$ .
- SRAM Figures of Merit:
 

Read current ( $I_{Cell}$ )

Stand-By Current ( $I_{sb}$ )

Write Margin (WM)

Static Noise Margin (SNM)

### 3. MAIN ELECTRICAL CHARACTERISTICS OF NHVTPDSP TRANSISTORS

$W=0.18\mu\text{m}$ ,  $L=0.1\mu\text{m}$

PARAMETERS	SS	SF	TT	FS	FF	Units
VTLIN	573	583	514	444	452	mV
ION	44.05	47.8	57.3	66.4	74.6	$\mu\text{A}$
IOFF	0.48	1.32	2.28	6.76	15.5	pA
IG_ON	0.23	0.45	0.49	0.53	1.02	pA
IG_OFF	-63.6	131.7	-131.7	-131.7	-272.3	fA

### 4. MAIN ELECTRICAL CHARACTERISTICS OF NHVTPGSP TRANSISTORS

$W=0.12\mu\text{m}$ ,  $L=0.115\mu\text{m}$

PARAMETERS	SS	SF	TT	FS	FF	Units
VTLIN	521	533	465	394	407	mV
ION	31.8	36.2	43.7	51.8	59.8	$\mu\text{A}$
IOFF	0.37	0.85	1.89	8.04	12.48	pA
IG_ON	0.18	0.35	0.38	0.42	0.83	pA
IG_OFF	-39.5	-84.8	-84.8	-84.8	-181	fA

### 5. MAIN ELECTRICAL CHARACTERISTICS OF PHVTPUSP TRANSISTORS

$W=0.11\mu\text{m}$ ,  $L=0.1\mu\text{m}$

PARAMETERS	SS	SF	TT	FS	FF	Units
VTLIN	604	521	557	601	520	mV
ION	10.43	17.7	15.3	13	21.9	$\mu\text{A}$
IOFF	23	2110	297	66	4801	fA
IG_ON	51.2	117.7	114.3	108.9	24.6	fA
IG_OFF	-2.84	-5.66	-5.66	-5.66	-11.08	fA

### 6. MAIN ELECTRICAL CHARACTERISTICS OF SINGLE PORT SRAMS

$1.15\mu\text{m}^2$

PARAMETERS	SS	SF	TT	FS	FF	Units
Isb per Cell	1.32	5.97	6.19	16.6	44.6	pA
ICell	19.98	22.65	28.09	34.02	39.34	$\mu\text{A}$
WM	398.1	348.1	431.1	525.1	475.1	mV
SNM	257.9	271.1	235.1	190.0	203.9	mV

## 7. COMPARISON VERSUS PREVIOUS RELEASE

1.15 $\mu\text{m}^2$

SRAM Single Port 1.15 $\mu\text{m}^2$		V1.4.x
ICell ( $\mu\text{A}$ )	TT 1.2V 25C	28
	SS 1.08V 125C	12.2
Isby (pA/cell)	TT 1.2V 25C	6.2
	FF 1.32V 25C	56.1
SNM (mV)	TT 1.2V 25C	235
	FS 1.08V 125C	156
WM (mV)	TT 1.2V 25C	431.1
	SF 1.08V -40C	275.1

## 8. MISMATCH PARAMETERS CHANGE

AVT (mV. $\mu\text{m}$ )	V1.4.x
Pass Gate	5.15
Pull Down	6.07
Pull Up	5.04